

PROBING DEVICE

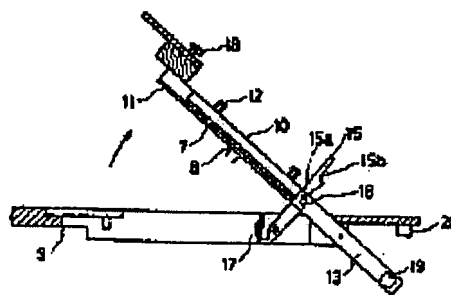
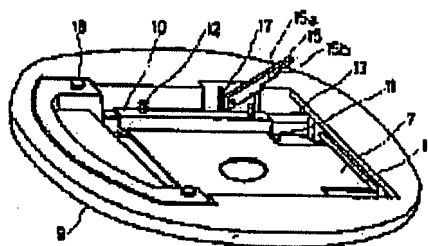
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- **International:** G01R31/26; H01L21/66
- **European:**
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Abstract of JP63318745

PURPOSE: To shorten the exchange time of a probing card, and to prevent the generation of the strain of the probing card by rotatably constituting at least a probing-card holding section for a probing card holder and turning and exchanging the probing-card holding section when the probing card is exchanged.

CONSTITUTION: A probing card holder 9 holding a probing card is installed to a probing device in which the probing card is exchanged with the probing card corresponding to the kind of a substrate to be measured and the substrate to be measured is measured, one part of at least a probing-card holding section for the probing card holder 9 is organized rotatably as a shaft, and the probing-card holding section is rotated and the probing card is exchanged when the probing card is replaced. A holder 10 having an L-shaped section is mounted so as to be able to hold the probing card 7 by both end sections to the probing card holder 9, and two arms 13 supporting the probing card 7 and the holder 10 are set up rotatably centering around the shaft 14. A stopper 15 supporting the arms 13 at a specific angle when the arms 13 are revolved is fitted.



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